

<b>Notice of References Cited</b>		Application/Control No. 10/532,082	Applicant(s)/Patent Under Reexamination OCHI ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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